

# Defect Analysis In Electron Microscopy

by M. H Loretto; R. E. Smallman

Microsc Res Tech. 2006 May;69(5):330-42. Atomic scale defect analysis in the scanning transmission electron microscope. Arslan I(1), Browning ND. Catalog Record: Defect analysis in electron microscopy Hathi Trust . Defect analysis in electron microscopy: Amazon.co.uk: M. H Loretto Scanning Electron Microscopy Metallurgical Associates Scanning Electron Microscopy / Micro-Analysis . related to cause of failure. Scanning Electron Microscope image of a casting defect in an aluminum casting Introduction to Transmission/Scanning Transmission Electron . Apr 26, 2003 . in the present paper the basic concepts of the transmission electron microscopy are outlined. In particular, the relevant aspects of both the Defect Analysis in Electron Microscopy Michael H. Loretto Springer By: Conference on Point Defect Behaviour and Diffusional Processes University of . Defect analysis in electron microscopy / M. H. Loretto and R. E. 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